

Form P.O.1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
H0001468SERIAL NO.  
09/692,814LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Honeywell International Inc.FILING DATE  
October 24, 2000GROUP  
1753

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>gm</i>	AA	2,949,357	08/1960	Resnick	140	421	
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## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>gm</i>	AM	JP1092338	04/1969	Japan				
	AN	GB 810533	03/1959	Great Britain				
	AO	JP57019372	02/1982	Japan				
	AP	JP200273623	10/2000	Japan				
<i>gm</i>	AQ	SU1582043	09/1996	SU				

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

*Robert J. Smith*

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>pm</i>	AA 5,939,788	08/1999	McTeer	057	751	
<i>pm</i>	AB 4,903,117	02/1990	Okamoto et al.	057	751	
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						Yes	No
<i>pm</i>	AM WO 00/13235	09/03/2000	PCT				
	AN 08120445	14/05/1996	Japan				
	AO FR 2 585 730 A1	08/01/1985	France				
	AP GB 2 202 237 A	21/09/1988	GB				
<i>pm</i>	AQ 11074348	16/03/1999	Japan				
	AR 2000012539	14/01/2000	Japan				

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<i>pm</i>	AS	Knotek et al., "The Structure and Composition of Ti-Zr-N, Ti-Al-Zr-N and Ti-Al-V-N Coatings" Materials Science and Engineering, A105/106, December 1988, pgs. 481-488.
<i>pm</i>	AT	Sakamoto et al., "Preparation and Microstructure of Reactively Sputtered Ti <sub>1-x</sub> Zr <sub>x</sub> N Films" Thin Solid Films 228, May 1993, pgs. 169-172.
	AU	

EXAMINER

*Anthony McDonald*

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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Jim</i>	AA	5,171,379	12/1992	Kumar et al.	148	432	
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>Jim</i>	AM	252,442	09.06.1960	Australia				
<i>Jim</i>	AN	55-179784	12/1980	Japan				
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>Jim</i>	AR	Hughes et al., "Grain Subdivision and the Development of Local Orientations in Rolled Tantalum" Tantalum, The Minerals, Metals & Materials Society, 1996, pgs. 257-262. (Year is sufficiently early so that the month is not an issue.)
	AS	Arlt, Jr., "Sulfonation and Sulfonation to Thorium and Thorium Compounds" Kirk-Othmer Encyclopedia of chemical Technology vol. 22, pp. 541-564, (1993). Year is sufficiently early so that the month is not an issue.
<i>Jim</i>	AT	Kirkbride et al., "The Effect of Yttrium on the Recrystallization and Grain Growth of Tantalum", J. Less-Common Metals, vol. 9, pp. 393-408, 1965. (Year is sufficiently early so that the month is not an issue.)

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*Anthony P. Donald*

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EV182656093

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## U.S. PATENT DOCUMENTS

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Document Number	Date	Country	Class	Subclass	Translation	
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

Z	AC	National Research Corporation Press Release, pgs. 1-4, July 1964.
	AD	National Research Corporation Data Sheet "SGS Tatalum", pgs. 1-7, no date.
	AD	ASTM Standard Specification for Tantalum and Tantalum Alloy Plate, Sheet, and Strip, pgs. 558-561, 1992. (Year is sufficiently early so that the month is not an issue.)
	AE	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Materials Research Society Symposium Proceedings, vol. 322, pgs. 413-422, 1994. (Year is sufficiently early so that the month is not an issue.)
	AF	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Refractory Metals & Hard Materials, vol. 12, pgs. 35-40, 1994. (Year is sufficiently early so that the month is not an issue.)
	AG	Klein et al., "Inhomogeneous Textures in Tantalum Sheets" Materials Science Forum, vol. 157-162, pgs. 1423, (1994). (Year is sufficiently early so that the month is not an issue.)
	AH	Clark et al., "Influence of Transverse Rolling on the Microstructural and Texture Development in Pure Tantalum", Metallurgical Transactions, vol. 23A, pgs. 2183-2191, August 1992.
	AI	Raabe, et al., "Texture and Microstructure of Rolled and Annealed Tantalum", Materials Science and Technology, Vol. 10, pgs. 299-305, April 1994.
	AJ	Wright et al., "Texture Gradient Effects in Tantalum", International Conference on Textures of Materials, 7 pgs., September 1993.
	AK	Wright et al., "Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate", Metallurgical Transactions A, 25A (1994), pgs. 1-17. (Year is sufficiently early so that the month is not an issue.)
Z	AL	Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047.
	AM	Kumar et al., "Corrosion Resistant Properties of Tantalum" Corrosion 95, Paper No. 253, 14 pages. (No date)
	AN	
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*Barney M. Donald*

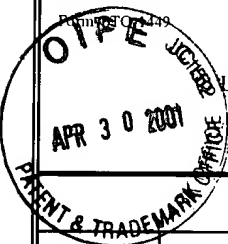
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Form PTO-159 <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>		ATTY. DOCKET NO. H0001468 (H058-044)		SERIAL NO. 09/695,814			
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)							
APPLICANT Honeywell International, Inc. (Pennsylvania)				FILING DATE October 24, 2000			
				GROUP Unassigned			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
epm	AA 6,024,847	02/15/00	Rosenberg et al.	304	243.1		
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EXAMINER <i>Robert M. Donald</i>				DATE CONSIDERED <i>1-14-03</i>			
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<i>Yan</i>	AA	60/225,518 (Serial No.) As filed and amended		Jianxing Li et al.			08/15/00	
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EXAMINER: <i>John M. Vercel</i>				DATE CONSIDERED: <i>1-14-03</i>				
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